

Capacitor, Tantalum, SMD, MnO2, Molded, 10 uF, 3216, +/-20% Tol, -55/+125C, 20 VDC (85C)



| General Information | |
|------------------------|--------------------|
| Supplier: | KEMET |
| Application: | General Purpose |
| Part Type Description: | SMD, MnO2, Molded |
| Construction: | Standard Chip-MnO2 |
| Body Type: | SMD Chip |
| Footprint: | 3216 |
| Weight: | 58.6 mg |
| RoHS: | Yes |

| Dimensions (mm) | | |
|-----------------|-----------|-----------|
| Symbol | Dimension | Tolerance |
| L | 3.2 | +/-0.2 |
| W | 1.6 | +/-0.2 |
| H | 1.6 | +/-0.2 |
| F | 1.2 | +/-0.1 |
| S | 0.8 | +0.2/-0.3 |
| B | 0.4 | +/-0.15 |
| X | 0.1 | +/-0.1 |
| P | 0.4 | REF |
| R | 0.4 | REF |
| T | 0.13 | REF |
| A | 1.2 | MIN |
| G | 1.1 | REF |
| E | 1.3 | REF |

| Specifications | |
|-------------------------|------------------------|
| Capacitance: | 10 uF |
| Tolerance: | +/-20% |
| Voltage: | 20 VDC (85C) |
| Voltage: | 13.4 VDC (125C) |
| Temperature Range: | -55/+125C |
| Current/Ripple Current: | 122 mAmps (100kHz 25C) |
| Current/Ripple Current: | 109.8 mAmps (85C) |
| Current/Ripple Current: | 48.8 mAmps (125C) |
| Resistance/ESR: | 5 Ohms (100kHz) |
| Failure Rate: | N/A |
| Leakage Current: | 2 uA |
| Dissipation Factor: | 10% |

| Packaging Specifications | |
|--------------------------|-------------|
| Package Kind: | T&R |
| Package Size: | 7 in/180 mm |
| Package Quantity: | 2000 |

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